

# AUIRF3007

HEXFET® Power MOSFET

#### **Features**

- Advanced Planar Technology
- Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified\*

V <sub>(BR)DSS</sub>	75V
R <sub>DS(on)</sub> typ.	10.5m $\Omega$
max	<b>12.6m</b> $Ω$
I <sub>D</sub> (Silicon Limited)	80A
D (Package Limited)	75A

### **Description**

Specifically designed for Automotive applications, this Stripe Planar design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.



G	D	S
Gate	Drain	Source

### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	80	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, VGS @ 10V (Silicon Limited)	56	Α
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	75	
I <sub>DM</sub>	Pulsed Drain Current ①	320	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) <sup>②</sup>	280	mJ
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value ⑦	946	
I <sub>AR</sub>	Avalanche Current ①	See Fig. 12a, 12b, 15, 16	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ®		mJ
$T_{J}$	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

### Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		0.74	
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

HEXFET® is a registered trademark of International Rectifier.

<sup>\*</sup>Qualification standards can be found at http://www.irf.com/

### Static Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	75			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.084		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		10.5	12.6	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 48A ⊕
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$
gfs	Forward Transconductance	180			S	$V_{DS} = 25V, I_D = 48A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 75V, V_{GS} = 0V$
				250		$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-200		$V_{GS} = -20V$

### Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$Q_g$	Total Gate Charge		89	130		I <sub>D</sub> = 48A
$Q_{gs}$	Gate-to-Source Charge		21	32	nC	$V_{DS} = 60V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		30	45		V <sub>GS</sub> = 10V <sup>(4)</sup>
t <sub>d(on)</sub>	Turn-On Delay Time		12			$V_{DD} = 38V$
t <sub>r</sub>	Rise Time		80		1	$I_D = 48A$
t <sub>d(off)</sub>	Turn-Off Delay Time		55		ns	$R_G = 4.6\Omega$
t <sub>f</sub>	Fall Time		49			V <sub>GS</sub> = 10V ④
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead,
					nН	6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		1	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		3270			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		520		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		78		1	f = 1.0MHz, See Fig. 5
C <sub>oss</sub>	Output Capacitance		3500			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance		340	_	[	$V_{GS} = 0V, V_{DS} = 60V, f = 1.0MHz$
C <sub>oss</sub> eff.	Effective Output Capacitance ©		640		[	$V_{GS} = 0V$ , $V_{DS} = 0V$ to $60V$

### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			80®		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			320		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 48A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		85	130	ns	$T_J = 25^{\circ}C$ , $I_F = 48A$ , $V_{DD} = 38V$
Q <sub>rr</sub>	Reverse Recovery Charge		280	420	nC	di/dt = 100A/µs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	turn-or	time is	negligib	le (turn-on is dominated by LS+LD)

#### Notes

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- $\begin{tabular}{ll} \hline @ Starting $T_J=25^\circ$C, $L=0.24$mH \\ $R_G=25\Omega$, $I_{AS}=48A$, $V_{GS}=10V$. (See Figure 12). \\ \end{tabular}$
- $\label{eq:loss} \begin{array}{l} \text{ } \exists \quad I_{SD} \leq 48A, \text{ di/dt} \leq 330A/\mu s, \text{ } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}C \end{array}$
- 4 Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- $\ ^{\circ}$   $\ ^{\circ}$   $C_{oss}$  eff. is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$  .
- $\ \ \,$  This value determined from sample failure population, starting T  $_{J}=25^{\circ}C,\,L=0.24mH,\,R_{G}=25\Omega,\,I_{AS}=48A,\,V_{GS}=10V.$

### Qualification Information<sup>†</sup>

<b></b>					
		Automotive			
		(per AEC-Q101) ††			
Qualification	on Level	Comments: This part number(s) passed Automotive qualificat IR's Industrial and Consumer qualification level is granted extension of the higher Automotive level.			
Moisture S	Sensitivity Level	TO-220 N/A			
	Machine Model	Class M4(+/- 600V) †††			
		(per AEC-Q101-002)			
ESD	Human Body Model		Class H1C(+/- 2000V) <sup>†††</sup>		
ESD			(per AEC-Q101-001)		
	Charged Device	Class C5(+/- 2000V) <sup>†††</sup>			
	Model		(per AEC-Q101-005)		
RoHS Com	npliant	Yes			

- † Qualification standards can be found at International Rectifier's web site: http://www.irf.com/
- †† Exceptions (if any) to AEC-Q101 requirements are noted in the qualification report.
- ††† Highest passing voltage.

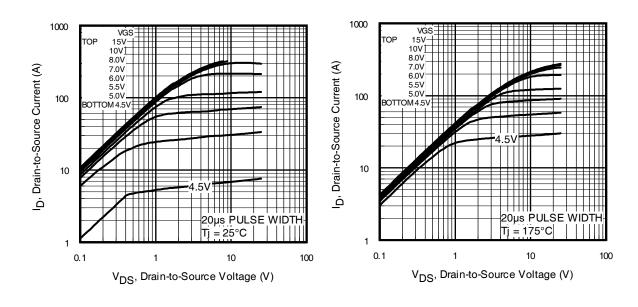


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

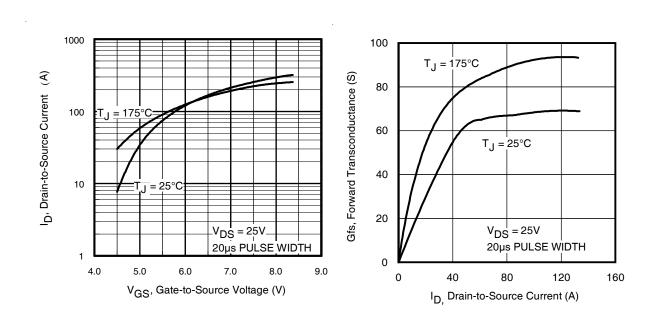
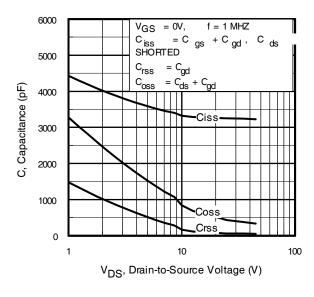
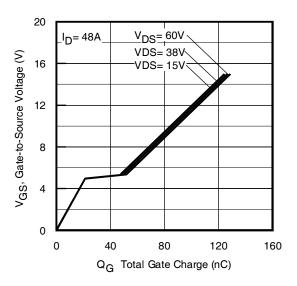


Fig 3. Typical Transfer Characteristics

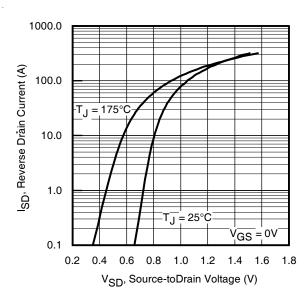
Fig 4. Typical Forward Transconductance Vs. Drain Current

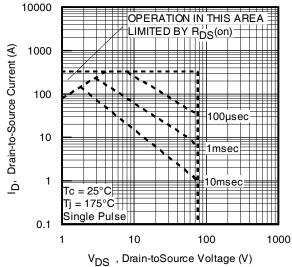




**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

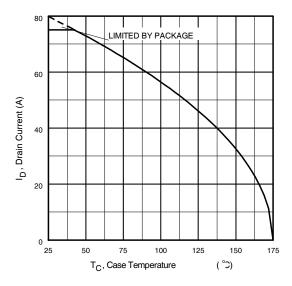
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

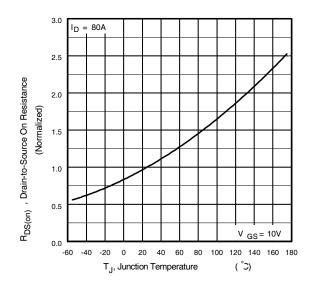




**Fig 7.** Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area





**Fig 9.** Maximum Drain Current Vs. Case Temperature

**Fig 10.** Normalized On-Resistance Vs. Temperature

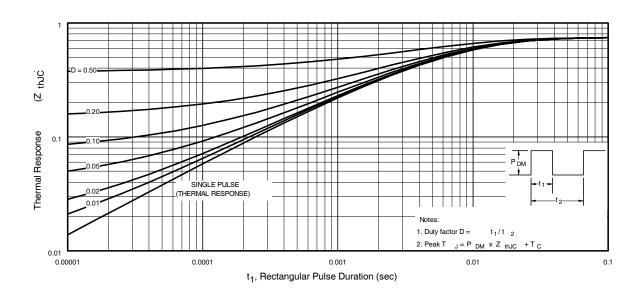


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

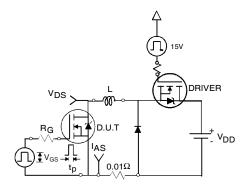


Fig 12a. Unclamped Inductive Test Circuit

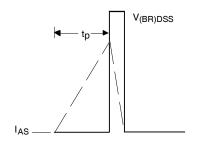


Fig 12b. Unclamped Inductive Waveforms

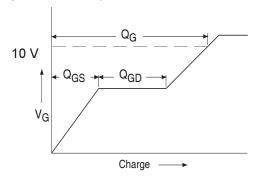


Fig 13a. Basic Gate Charge Waveform

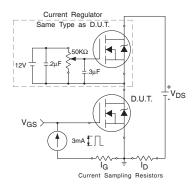
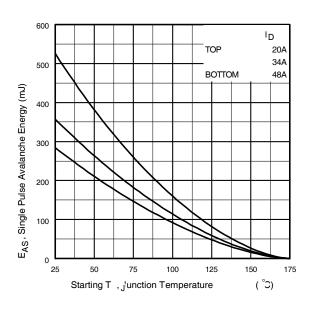


Fig 13b. Gate Charge Test Circuit



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

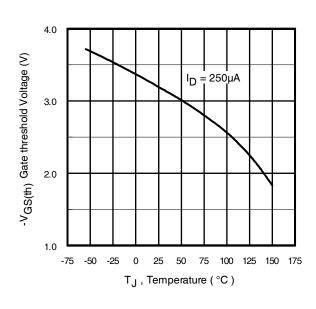


Fig 14. Threshold Voltage Vs. Temperature

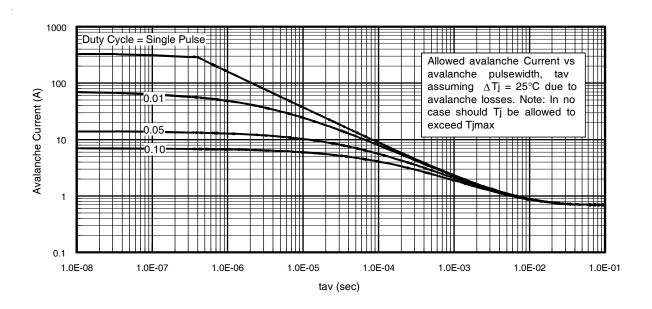


Fig 15. Typical Avalanche Current Vs. Pulsewidth

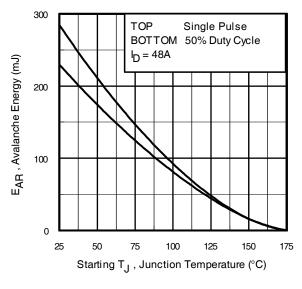


Fig 16. Maximum Avalanche Energy Vs. Temperature

## Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).
- t<sub>av =</sub> Average time in avalanche.
- $D = Duty cycle in avalanche = t_{av} \cdot f$

 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D~(ave)} &= 1/2~(~1.3 \cdot BV \cdot I_{aV}) = \triangle T/~Z_{thJC} \\ I_{av} &= 2\triangle T/~[1.3 \cdot BV \cdot Z_{th}] \\ E_{AS~(AR)} &= P_{D~(ave)} \cdot t_{av} \end{split}$$

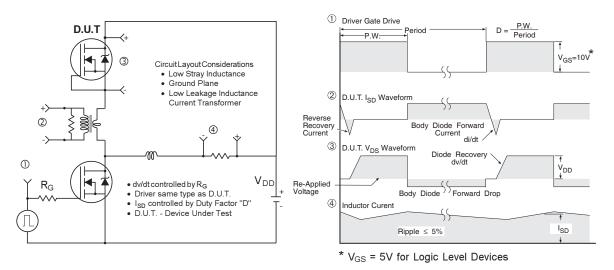


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

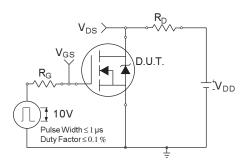


Fig 18a. Switching Time Test Circuit

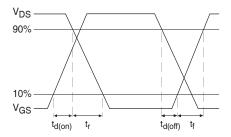
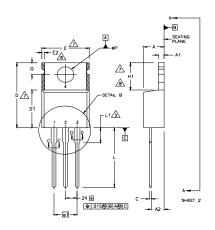
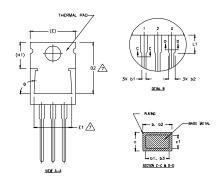


Fig 18b. Switching Time Waveforms

### TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





#### NOTES:

SYMBOL

A2 b b1 b2 b3

c c1

D1

D2 E E1 e e1 H1 L

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
  DIMENSIONS ARE SHOWN IN INCHES (MILLIMETERS).
  LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
  DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH
  SHALL NOT EXCEED, JOOS" (0.127) PER SIDE. THESE DIMENSIONS ARE
  MEASURED AT THE OUTERNOST EXTREMES OF THE PLASTIC BODY.
  DIMENSION D & C1 APPLY TO BASE METAL ONLY.
  CONTROLLING DIMENSION: INCHES.
  THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1

MILLIMETERS

MIN.

0.51

2.04

0.38 1.15 1.15 0.36

0,36

14 22

8.38 12.19

8.38

5.85 12.70

3,54

MAX

1,40

2.92

0.96 1.77 1.73 0.61

0.56

16.51

9.02

12.88

8 89

6.55 14.73

6.35 4.08

DIMENSIONS

MIN

.020

.080

.015

.045

560

.330

.480 .380 .330

.500

.139

MAX

.055

.115 .040 .038 .070

.068

.022

650 .355 .507

.420

.580

,250

NOTES

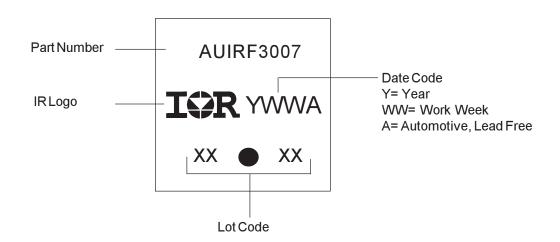
4,7 7

DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED,

### HEXFET

- IGBTs, CoPACK 1.- GATE 2.- COLLECTOR 3.- EMITTER
- DIODES

### TO-220AB Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

## Ordering Information

Base part number	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRF3007	TO-220	Tube	50	AUIRF3007

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